

# Private Circuits

## A Modular Approach

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## Surveillance Devices



*Credit card details*  
*SSN number*  
*Passwords*  
*PGP keys*  
*...*

## Surveillance Devices



## Side Channel Attacks

*Adversary can obtain partial information (leakage) about the computation*

# Leakage-Resilient Cryptography

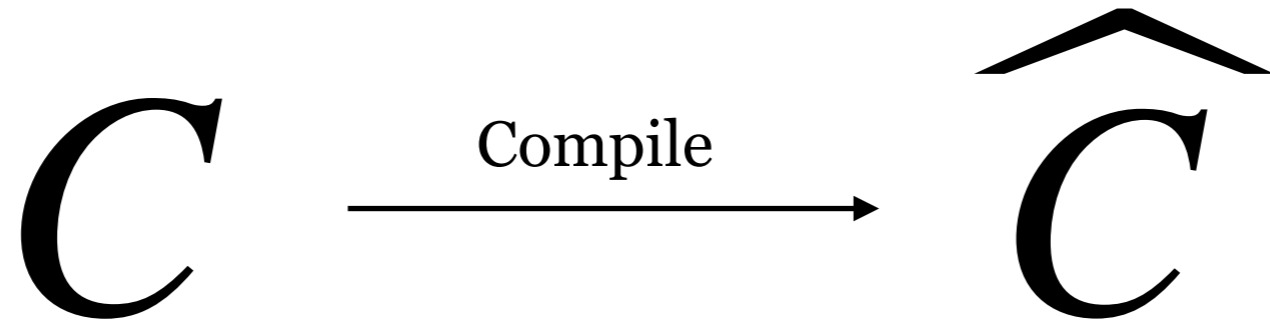
## GOAL

Protecting cryptographic schemes against  
side-channel attacks

This Work:

Leakage-Resilient Circuit Compilers  
[ISW03]

# Circuit Compilers



# Circuit Compilers

$$C \xrightarrow{\text{Compile}} \widehat{C}$$

$$x \xrightarrow[\text{\$ \$}]{\text{Encode}} \widehat{x}$$

$$\widehat{C}(\widehat{x}) \xrightarrow{\text{Decode}} C(x)$$

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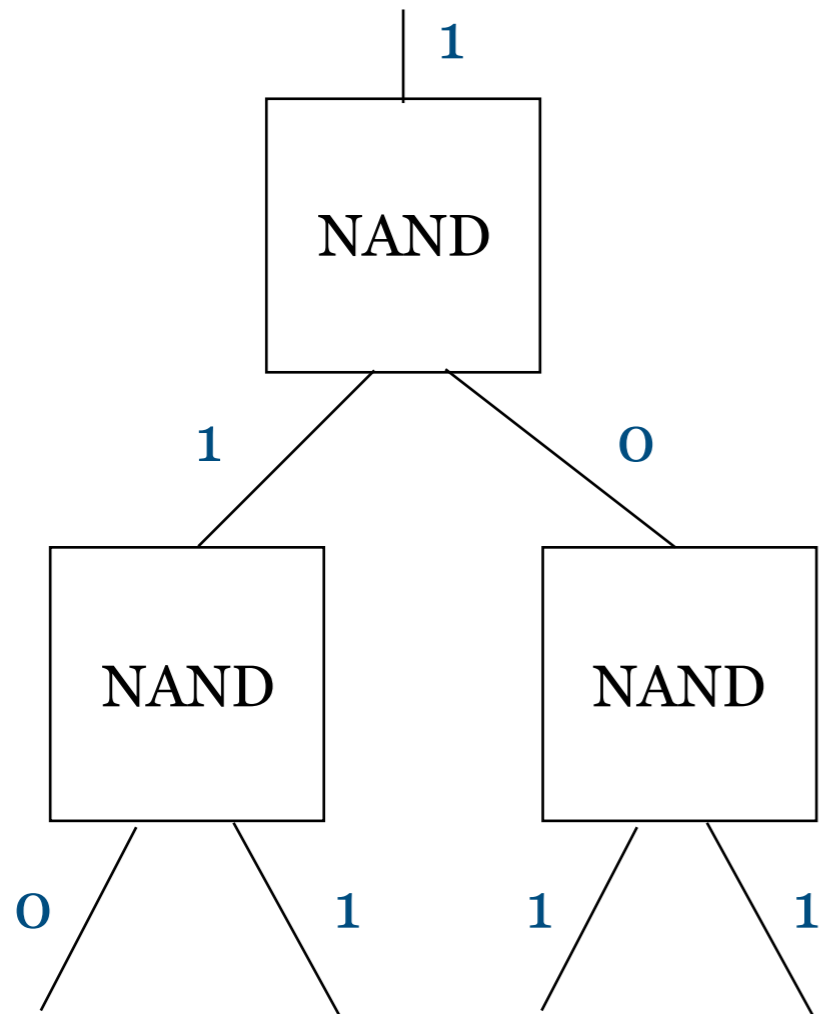
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- $\hat{C}$  can contain random-bit gates

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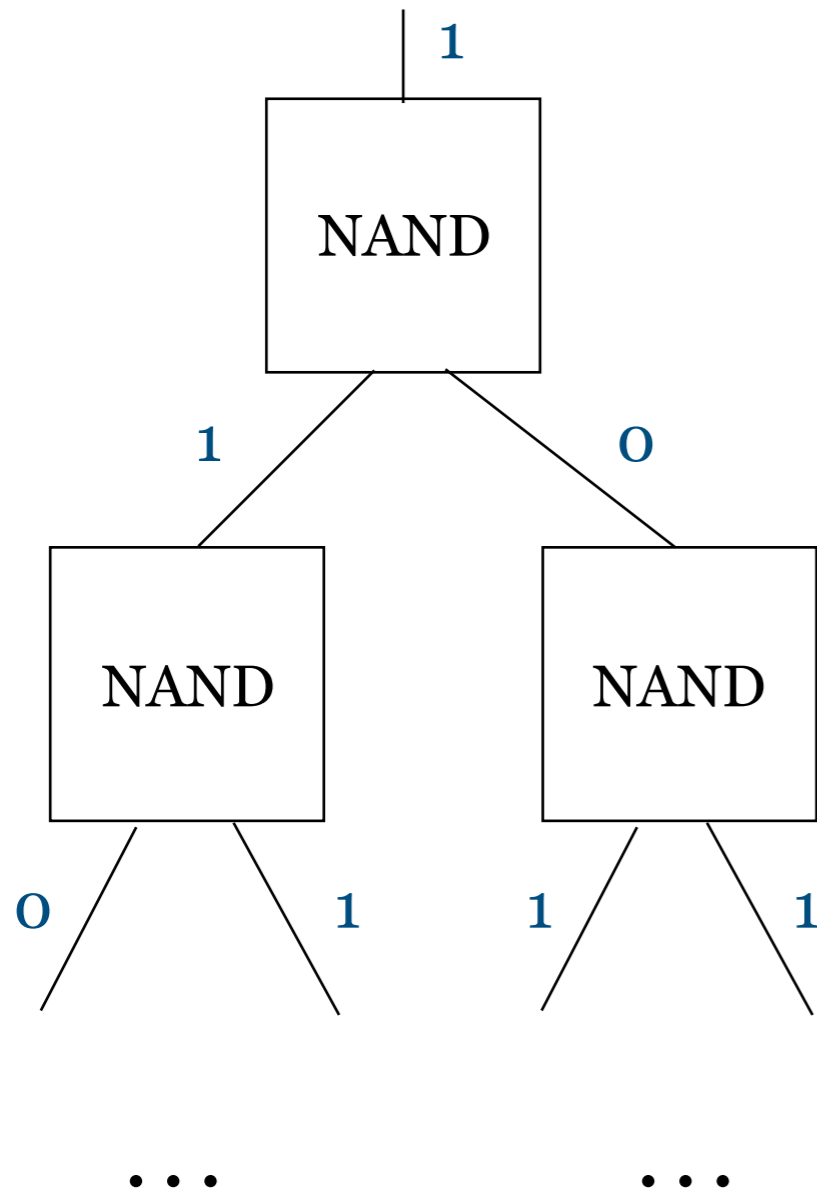


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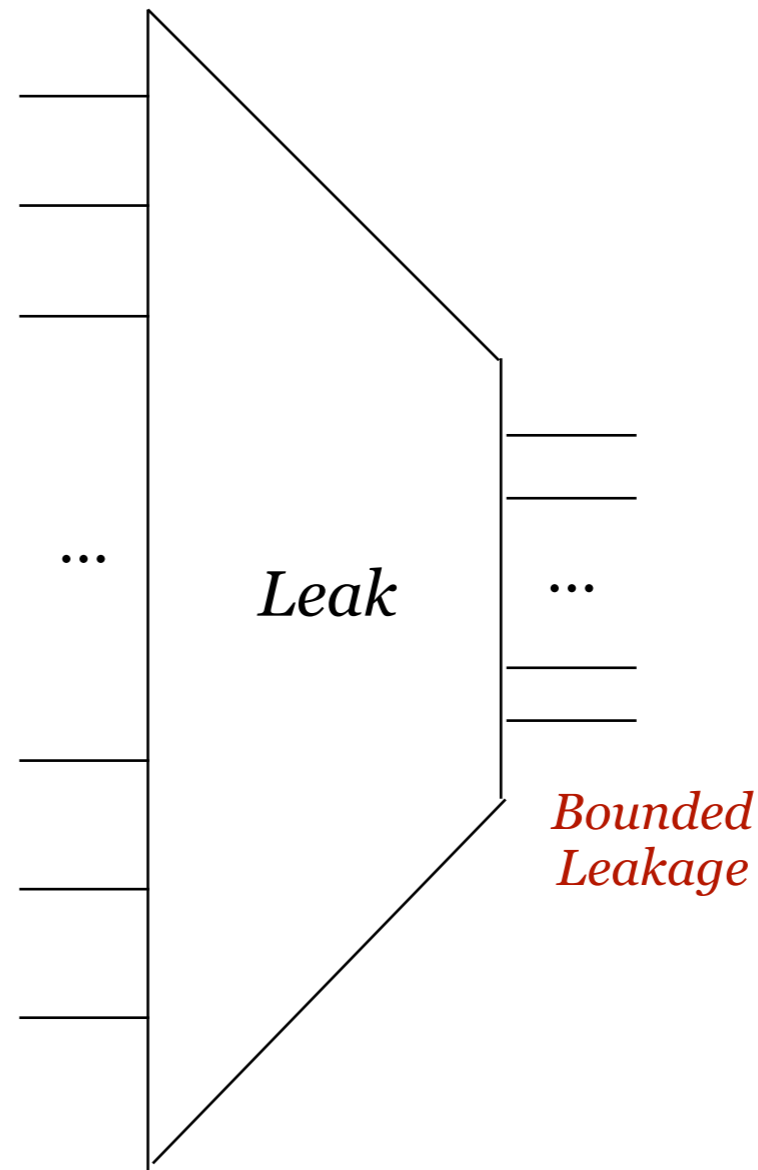
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$$\widehat{C}(\widehat{x})$$

# Leakage-Resilient Circuit Compilers



$$\widehat{C}(\widehat{x})$$



Leakage on computation of  $\widehat{C}$  on  $\widehat{x}$

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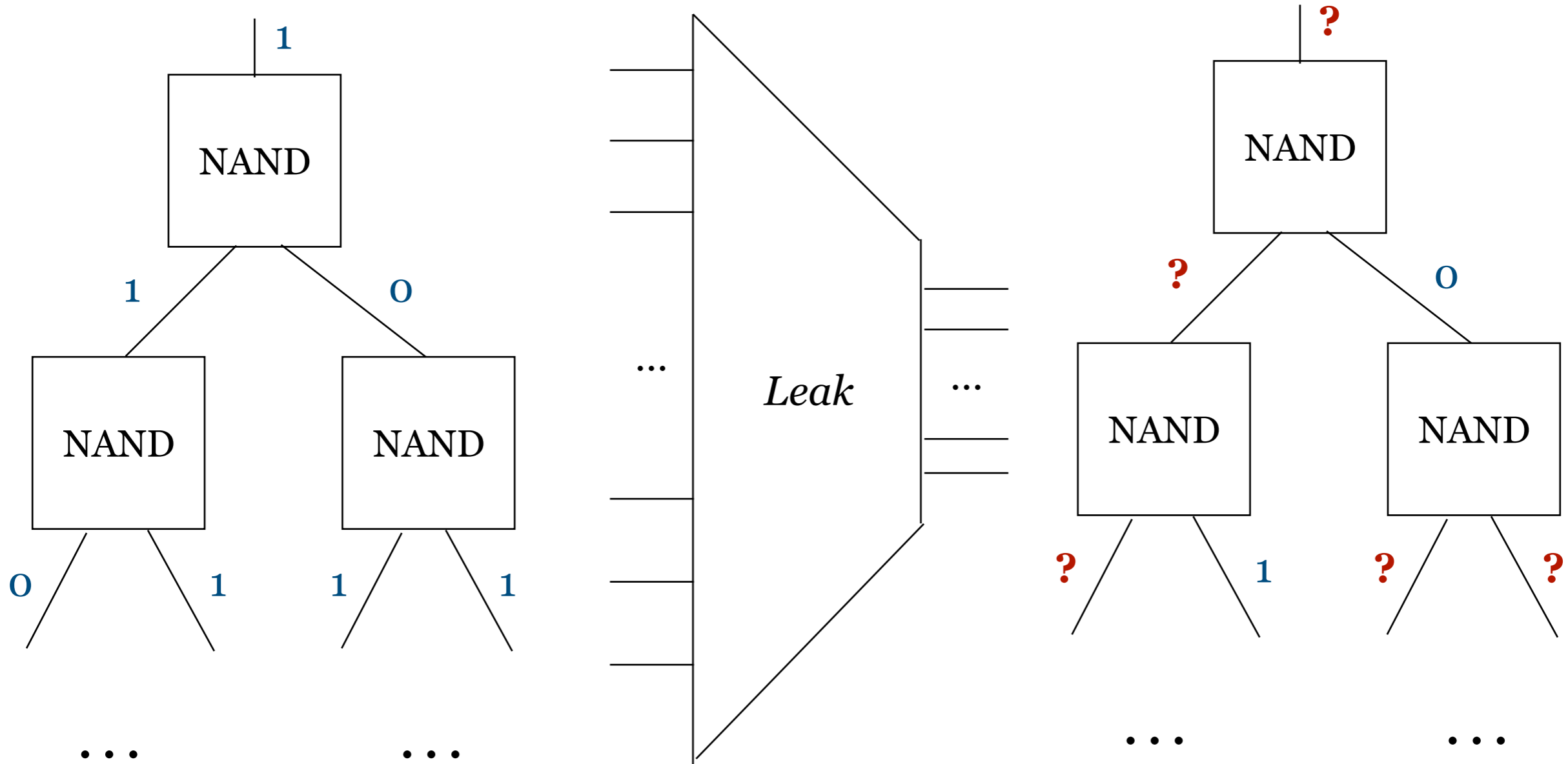
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  - *Wire-probing attacks [ISW03,...]*
  - *Split-state leakage-resilient compiler [MR03, DP08, GR12,...]*

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This Work!

# Wire-probing attacks [ISW03, ...]



Subset of values  
in the computation  
leaked

# Leakage-Resilience: Wire-probing attacks [ISW03,...]

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Following [ISW03], several works study this setting...  
[RP10,KHL11,GM11,CPR13,CGPQR12,...]

## **MPC on Silicon**

Applying MPC techniques to design secure hardware

# Leakage-Resilience: Wire-probing attacks [ISW03,...]

**Worst Case Leakage:** threshold  $t$

*- Any  $t$  wires are leaked*

Recent years: focus on randomness complexity

[IKLOPSZ<sub>13</sub>,BBPPTV<sub>16</sub>,BBPPTV<sub>17</sub>]

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Leakage resilient compilers for  $s$ -sized circuits and threshold  $t$

- secure against  $t$ -wire probing attacks
- compiled circuit has size  $s \cdot \text{poly}(t)$
- randomness complexity =  $t^{1+\varepsilon}$ , for any  $\varepsilon > 0$

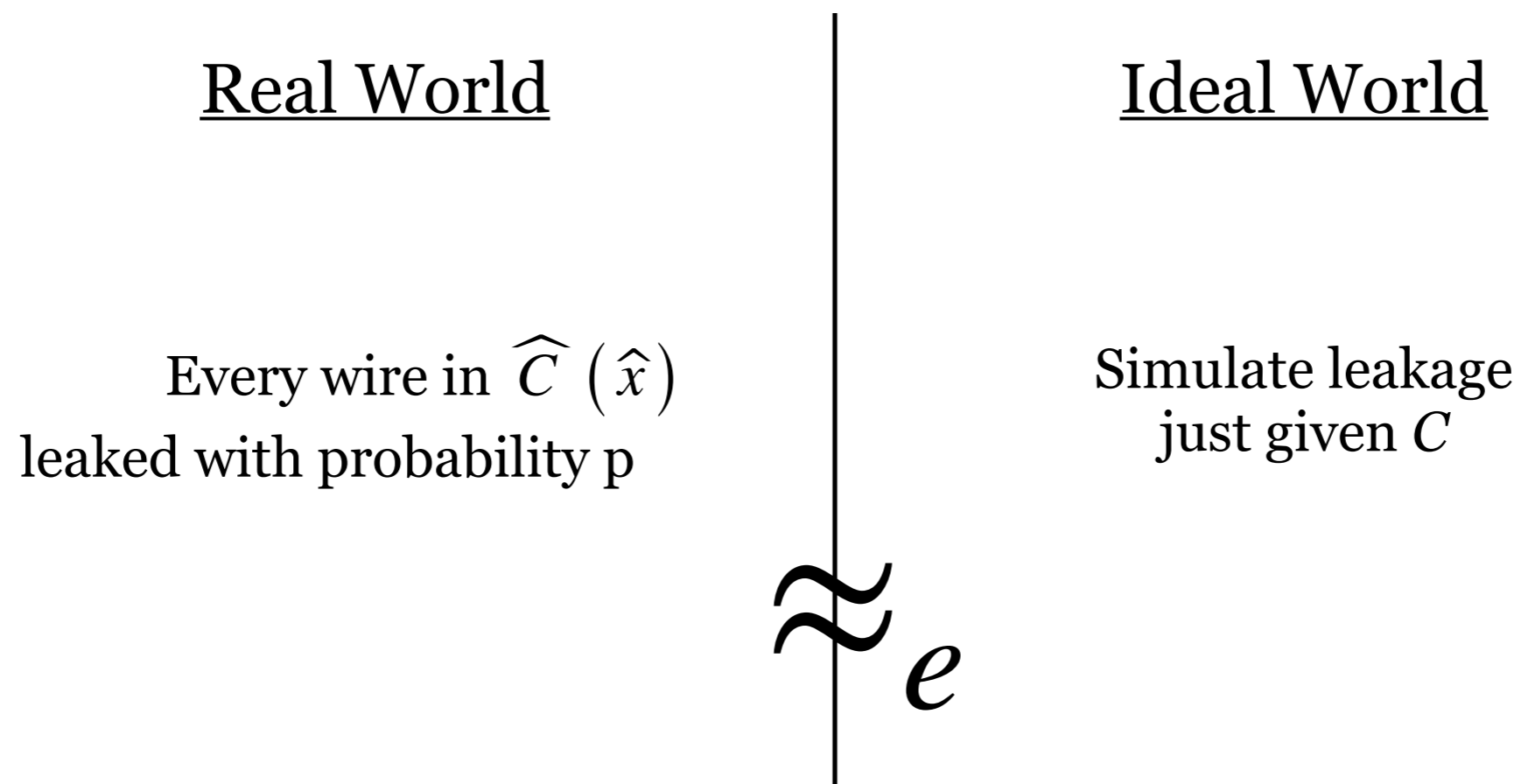


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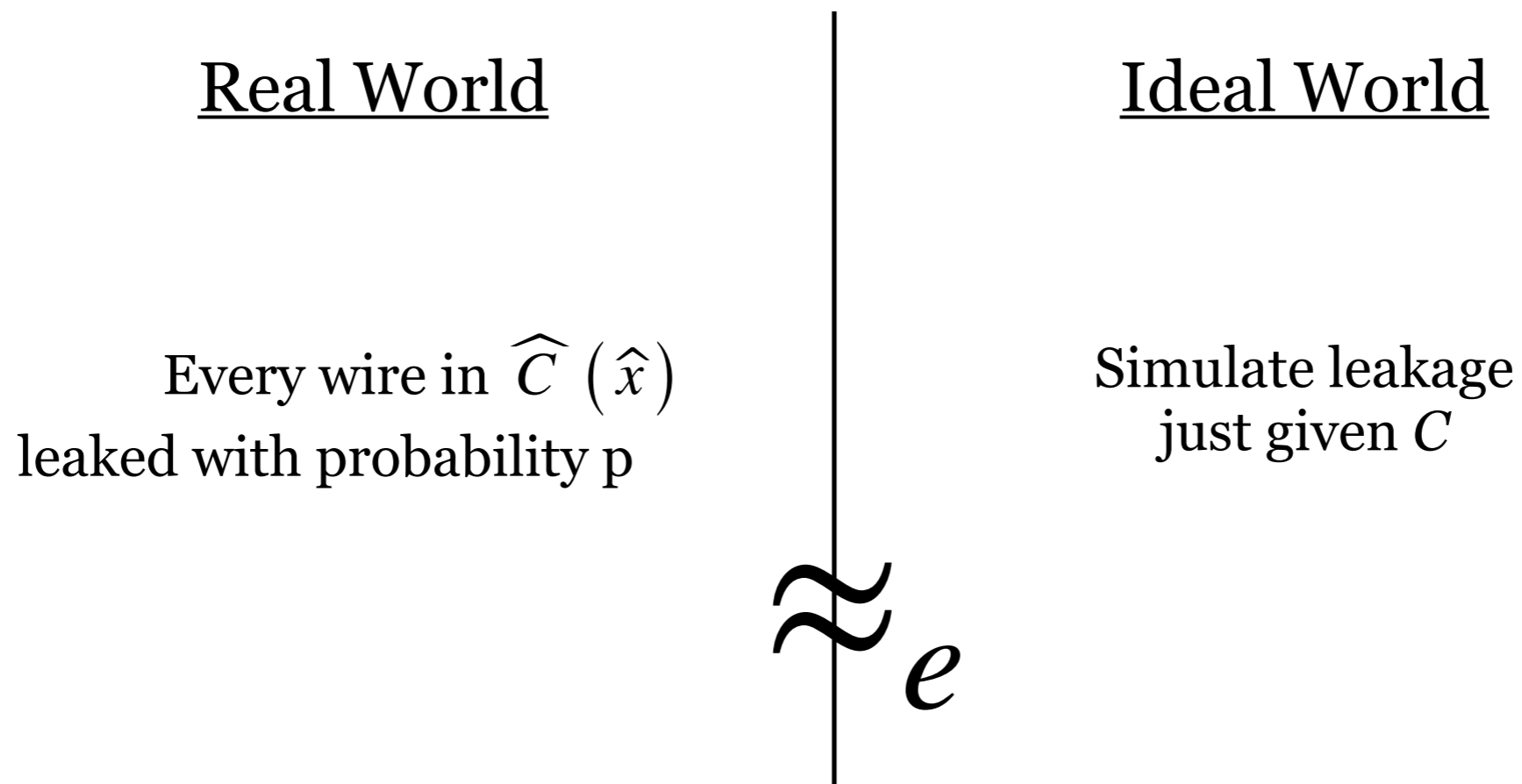
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# Leakage-Resilience: Random Wire-probing attacks

[ISW03,Ajtai10,ADF16]

**Probabilistic Leakage:** parameterized by  $(p,e)$



Related to Noisy Leakage Model: [CJJR99,FRRTV10,DDF15,...]

# Prior works: Random Wire-Probing Attacks

$p = \text{constant}$ ,  $e = \text{negligible}$

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- [Ajtai10]:
  - highly complex
- [ADF16]:
  - simplifies Ajtai's result
  - still uses heavy machinery (AG codes and expanders)

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Leakage-resilient circuit compiler against  $(p,e)$ -random probing attacks

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**p = 0.000065**



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- *Simple composition-based approach; uses only elementary tools*

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Leakage-resilient circuit compiler against  $(p,e)$ -random probing attacks

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Large gates: construction with  $p$  close to 1

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**This implies leakage-resilience!**

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A fraction of input and output will be leaked

- Probabilistic: *parameterized by  $(p, p', e)$*

Leakage simulatable given

- every bit of input  $\mathbf{x}$  w/ probability  $p'$
- every bit of output  $\mathbf{C}(\mathbf{x})$  w/ probability  $p'$



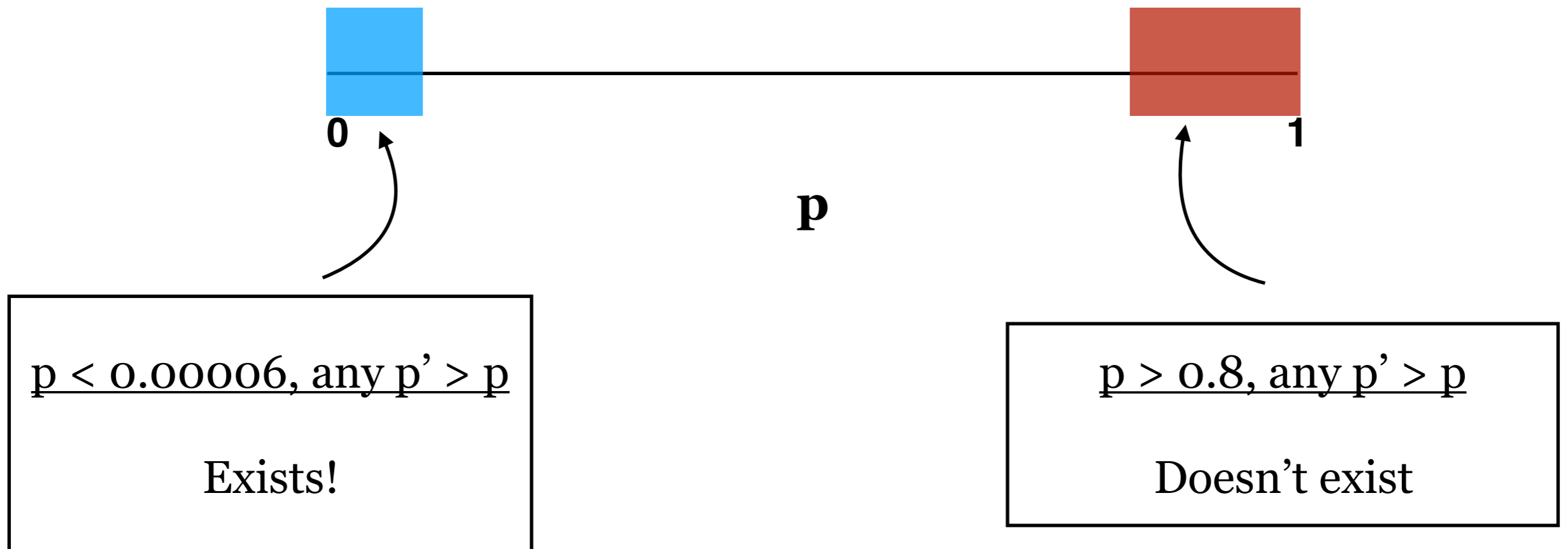
# Results: Leakage Tolerance

Worst Case: t-wire probing attacks

- construction: randomness complexity  $t^{1+\varepsilon}$
- lower bound: require at least  $t$  random-bit gates

# Results: Leakage Tolerance

Probabilistic Case:  $(p, p', e)$ -random probing attacks



# Techniques

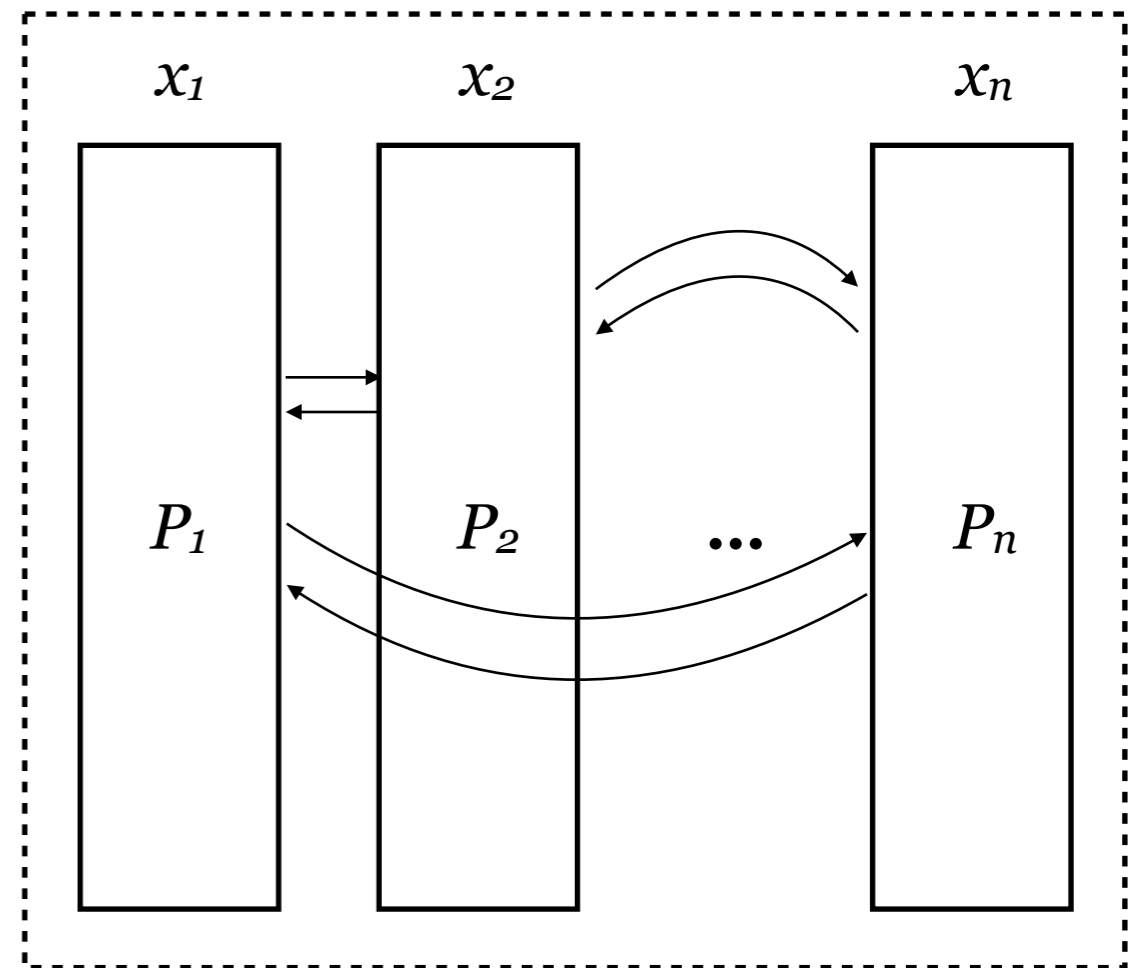
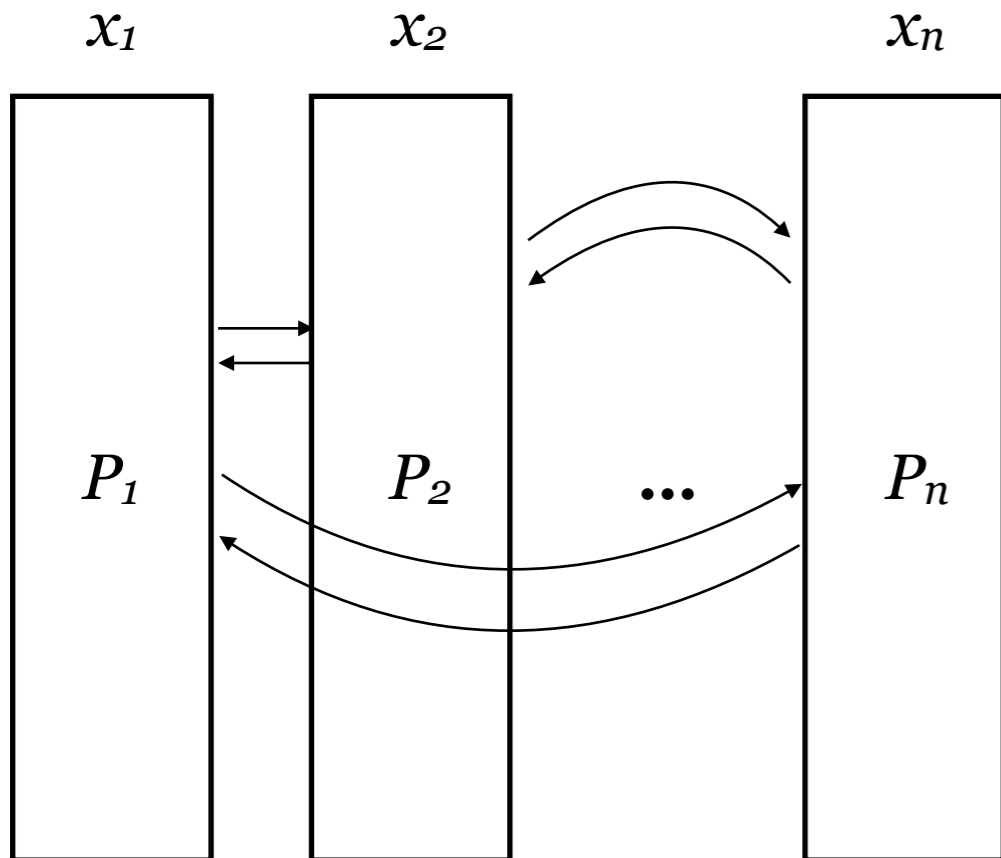
# Goal for this talk

- Leakage-resilient circuit compiler
- $(p,e)$ -random probing attacks

# Starting Point: t-out-n Secure MPC

$\Pi(C)$

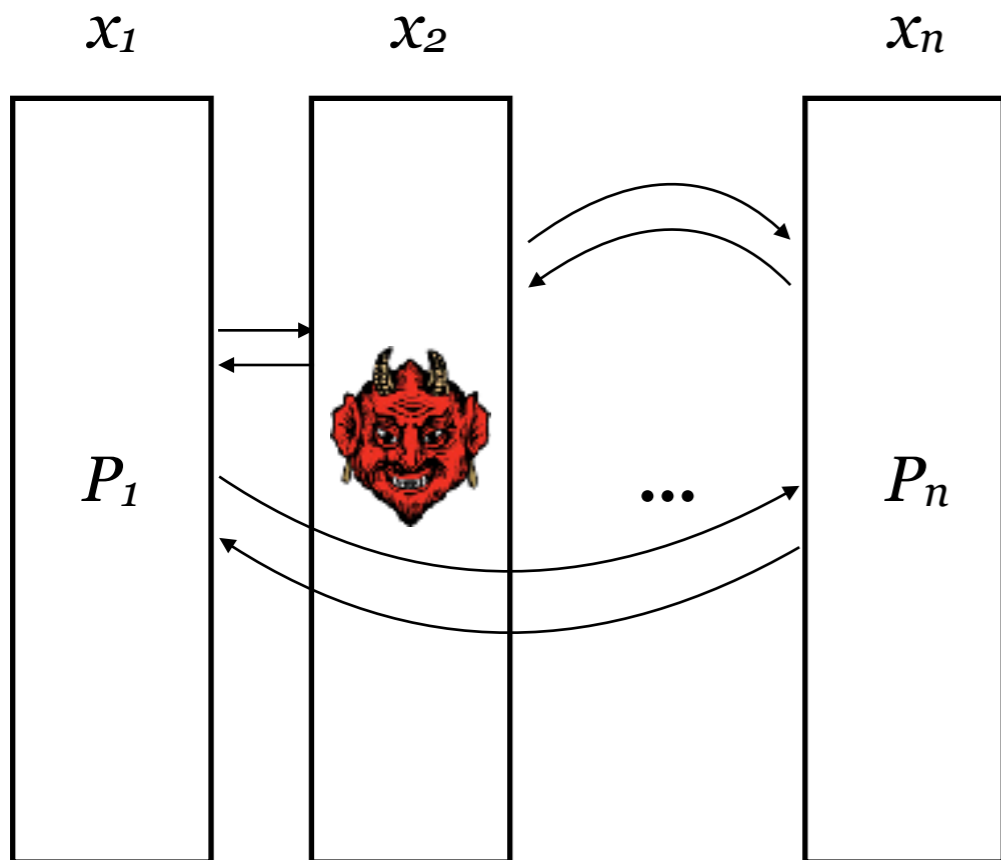
$\hat{C}$



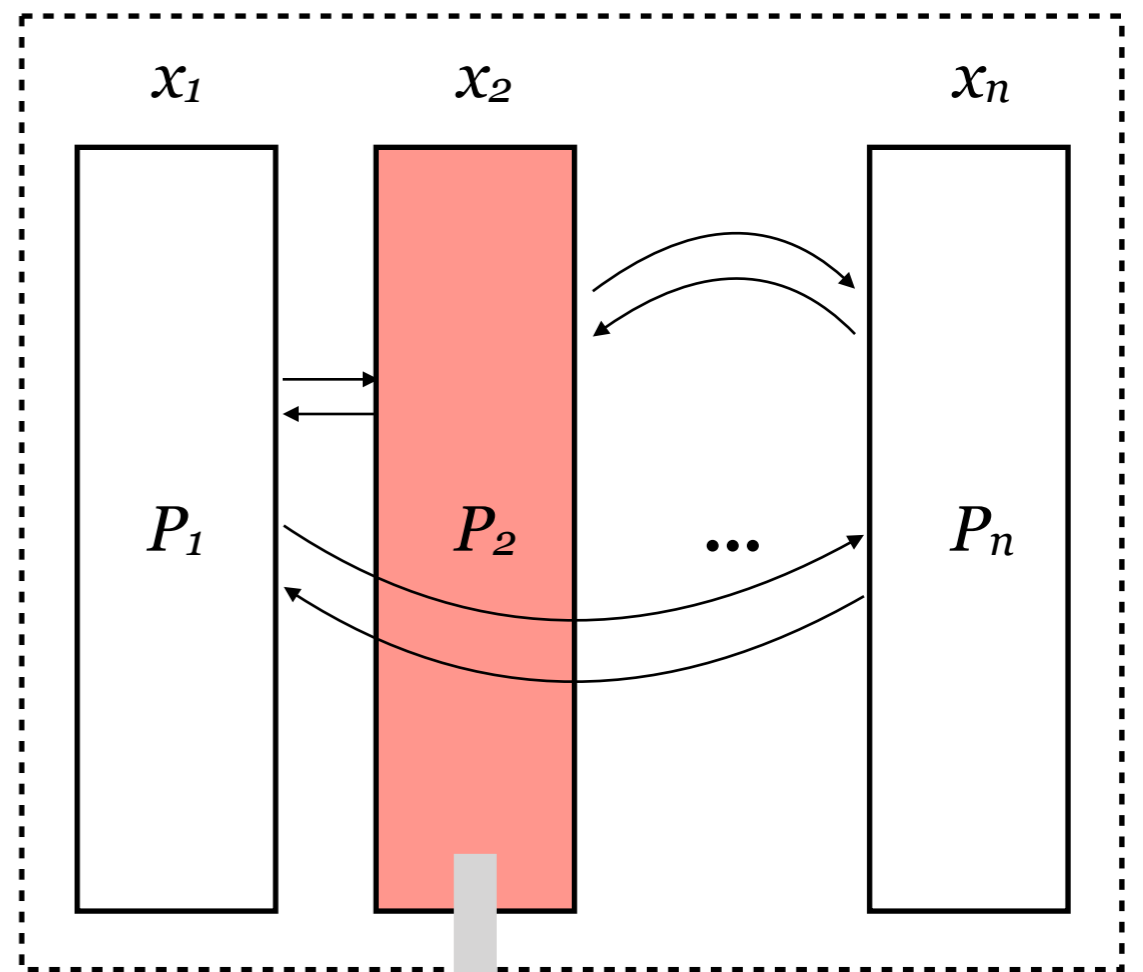
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$\Pi(C)$

$\hat{C}$



$\equiv$



**Passive  
Corruption of  $P_2$**

**Leak State of  $P_2$**

# Leakage-Resilient Circuit Compiler

$$\hat{C} = \Pi(C')$$

$C'$

**Input:** shares of  $x$

**Output:** shares of  $C(x)$

- *reconstruct  $x$*
- *compute  $C(x)$*
- *share  $C(x)$*

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Probability that more than  $t$  wires are leaked = Simulation error  $e$

$$\text{Simulation Error } e \leq \exp\left(\frac{-(1+t)^2}{12\text{poly}(|C|) \cdot p}\right) \quad (\text{by Chernoff})$$

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negligible??

# $(\mathbf{p}, \mathbf{e}_0)$ -Base Gadget $G_0$

Leakage-resilient circuit compiler

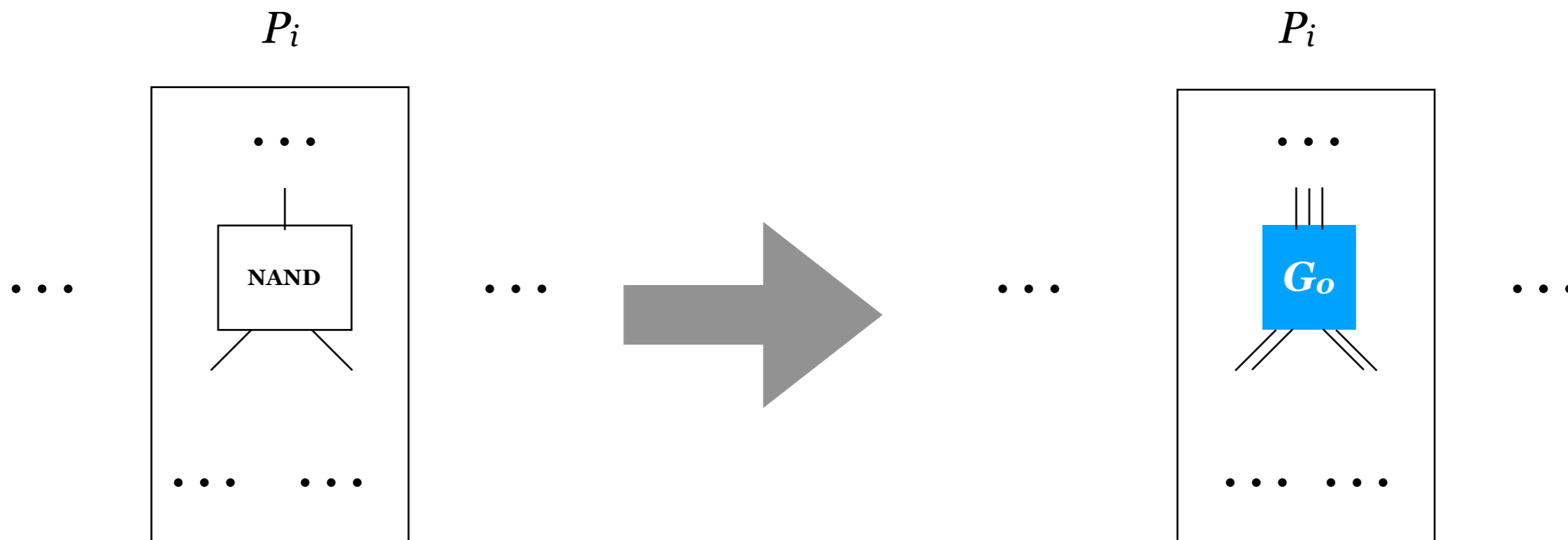
with

$\mathbf{p} = \text{constant}, \mathbf{e}_0 = \text{constant}$

# Reducing the Error

## IDEA

- Start with  $t$ -out- $n$  secure MPC
- Emulate every gate in  $t$ -out- $n$  secure MPC with  $(p, e_o)$ -base gadget  $G_o$



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Size?

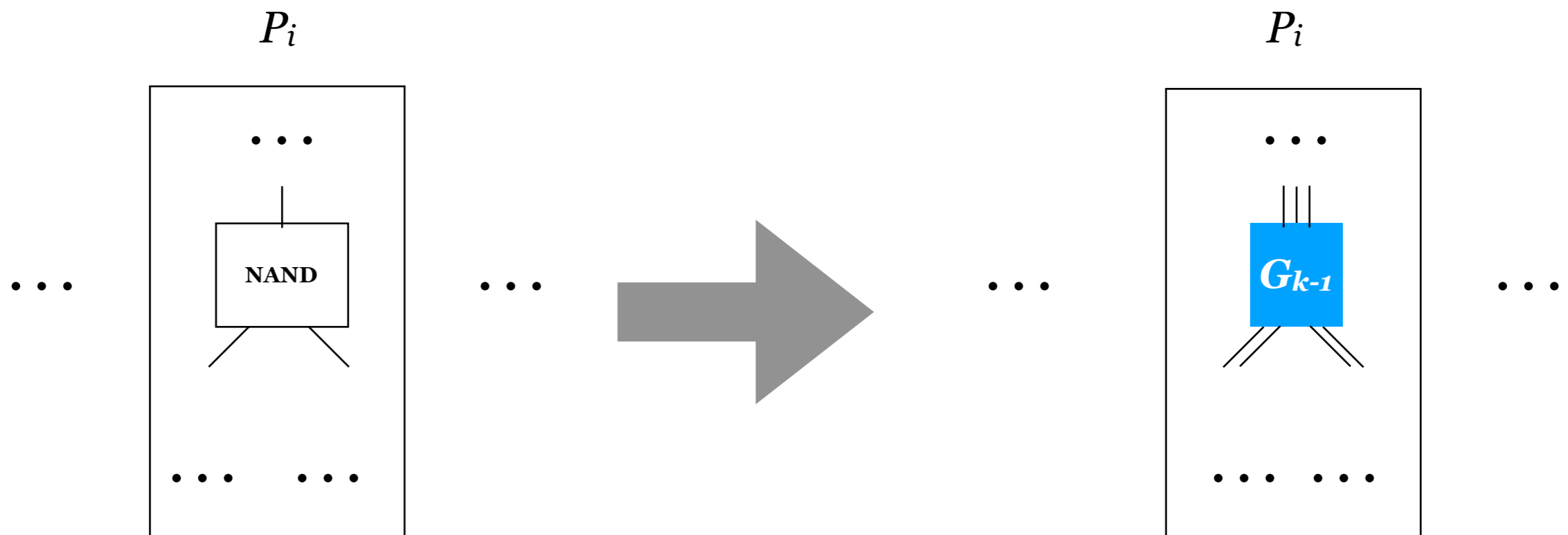
Size?

$$|\mathbf{Base\ Gadget}| \times |\Pi(C')|$$

# After k steps

## IDEA

- Start with  $t$ -out- $n$  secure MPC
- Emulate every gate in  $t$ -out- $n$  secure MPC with  $(p, e_{k-1})$ -gadget  $G_{k-1}$



# After k steps: size?

$$\begin{aligned} \text{Size of } k^{\text{th}} \text{ Gadget } G_k &\leq |(k-1)^{\text{th}} \mathbf{Gadget}| \times |\Pi(C')| \\ &\leq |(k-2)^{\text{th}} \mathbf{Gadget}| \times |\Pi(C')| \times |\Pi(C')| \\ &\quad \dots \\ &\leq (|\Pi(C')|)^k \end{aligned}$$

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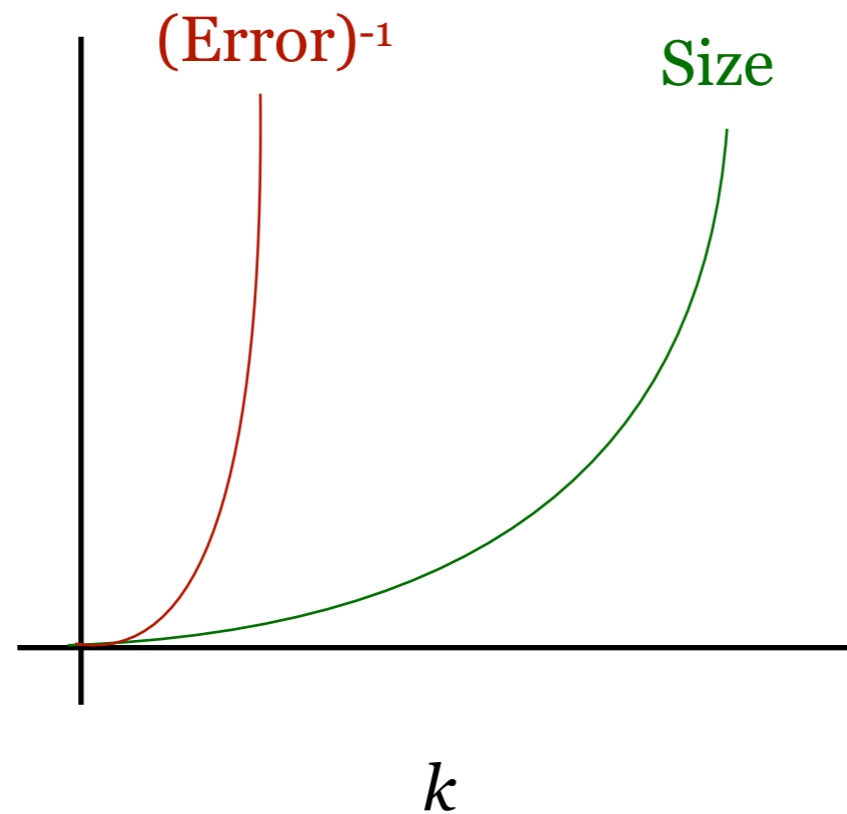
# After k steps: error

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When  $|C|$  is constant,

$$e_k \leq \exp(-2^{O(k)})$$

$$\text{Size of } k^{\text{th}} \text{ Gadget } G_k \leq \exp(O(k))$$



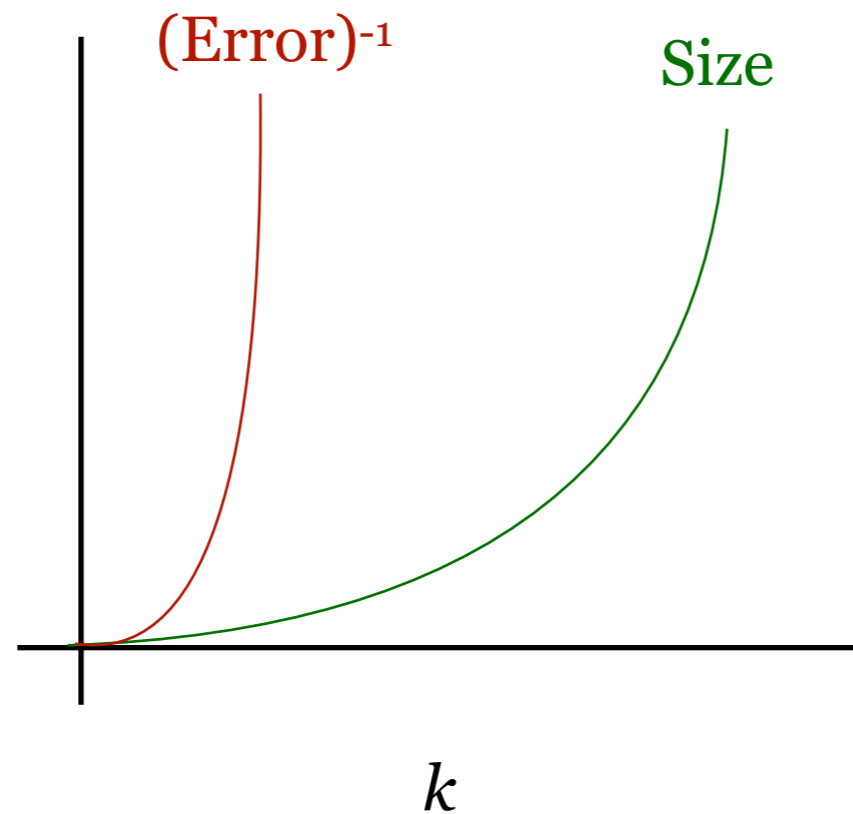


$$k = \log(|C|)$$

When  $|C|$  is constant,

$$e_k \leq \exp(-2^{O(k)}) = \text{negl}(|C|)$$

$$\text{Size of } k^{\text{th}} \text{ Gadget } G_k \leq \exp(O(k)) = \text{poly}(|C|)$$

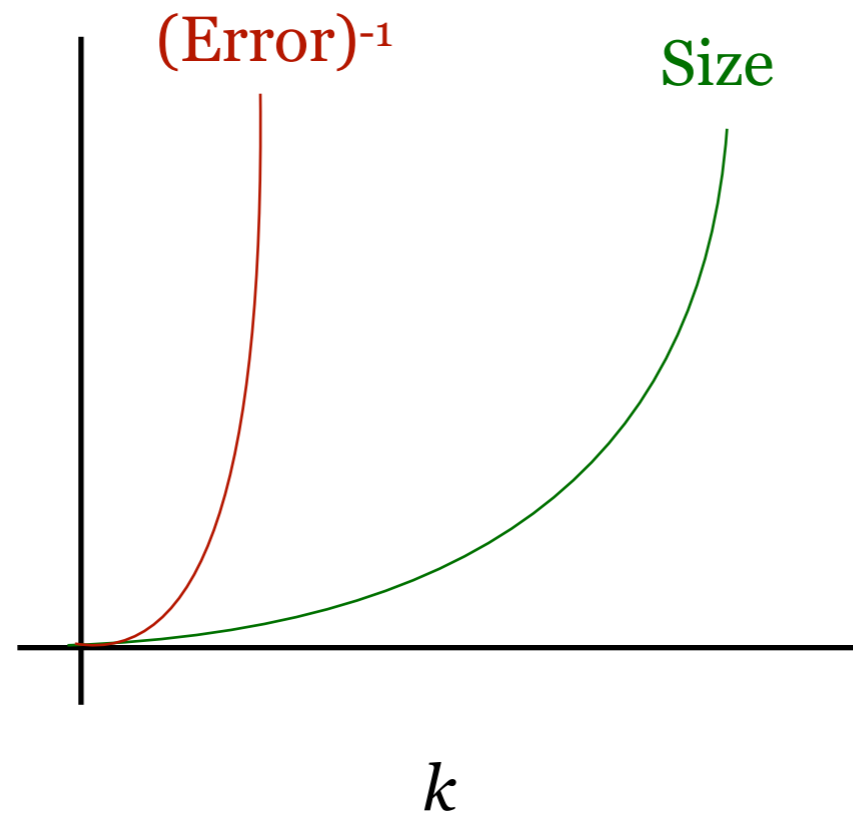


**C = NAND**

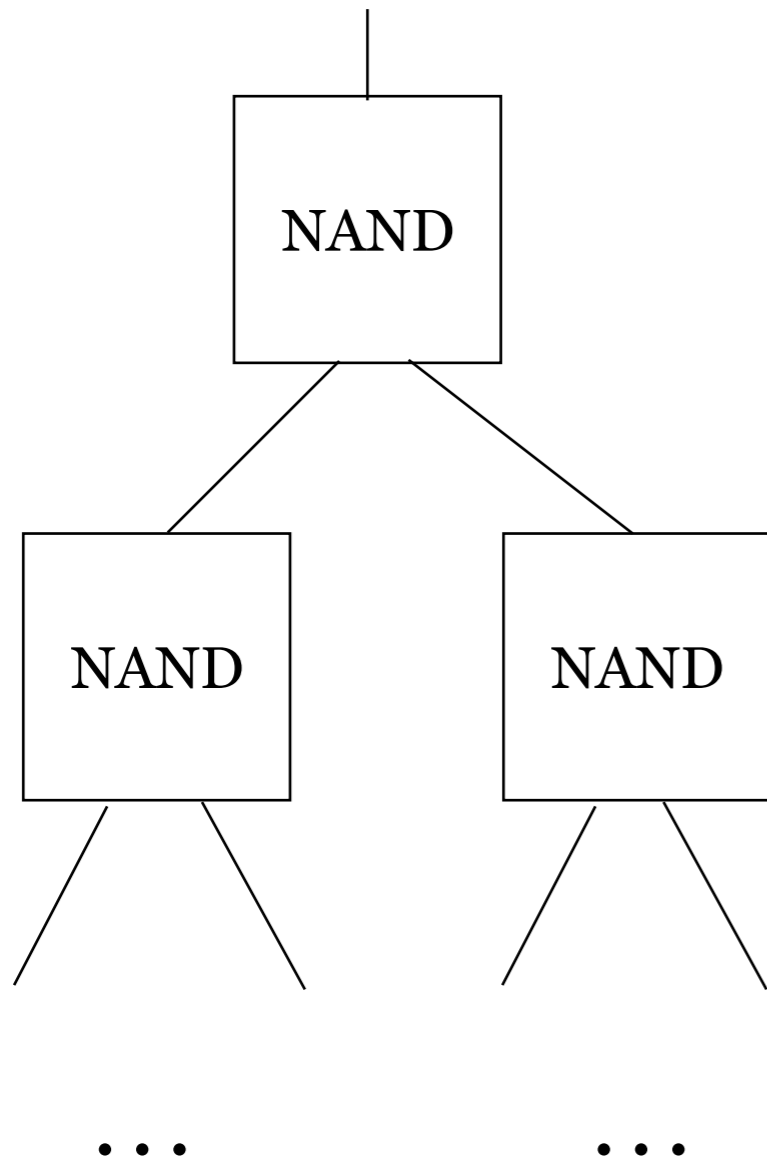
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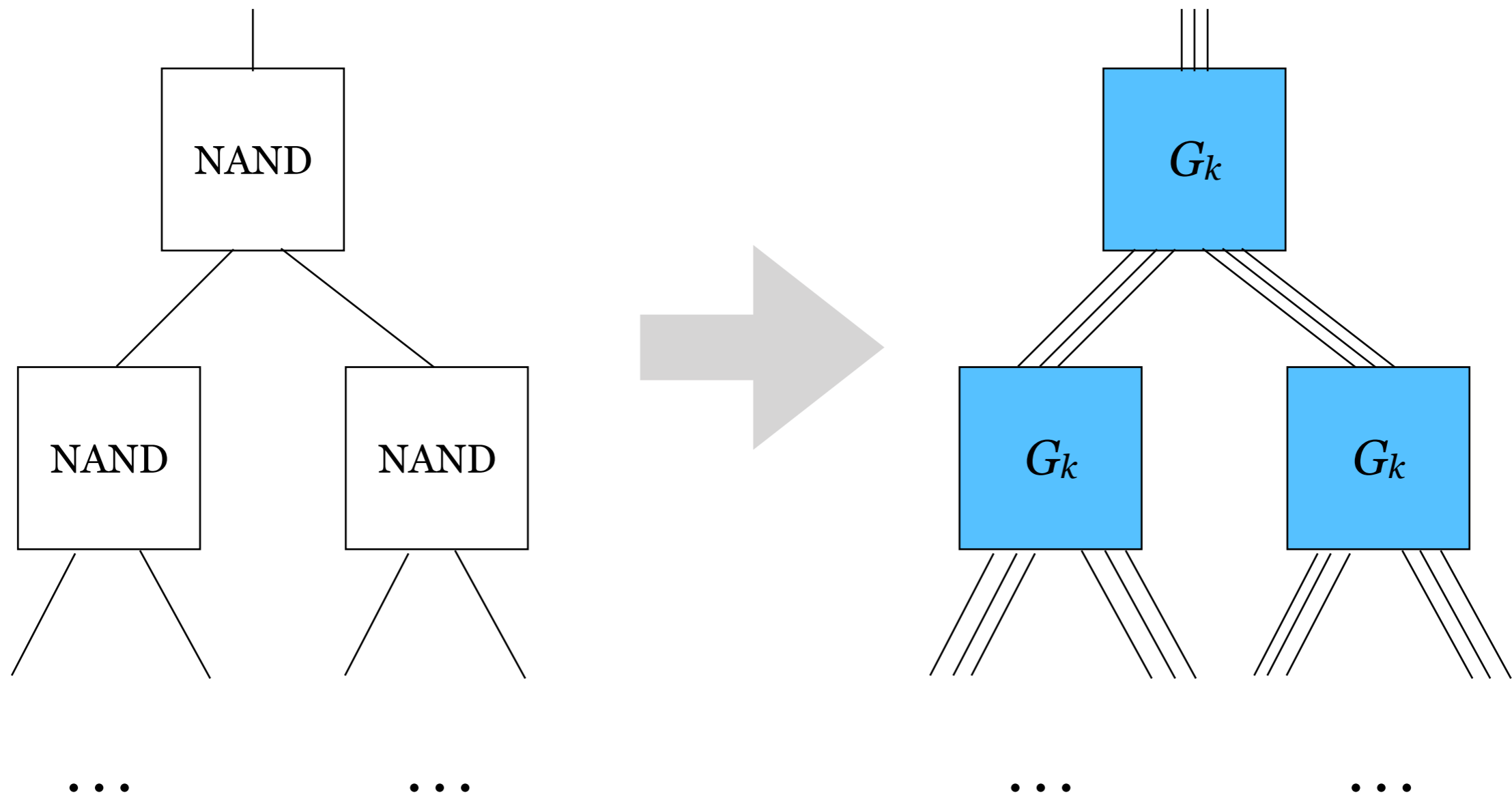
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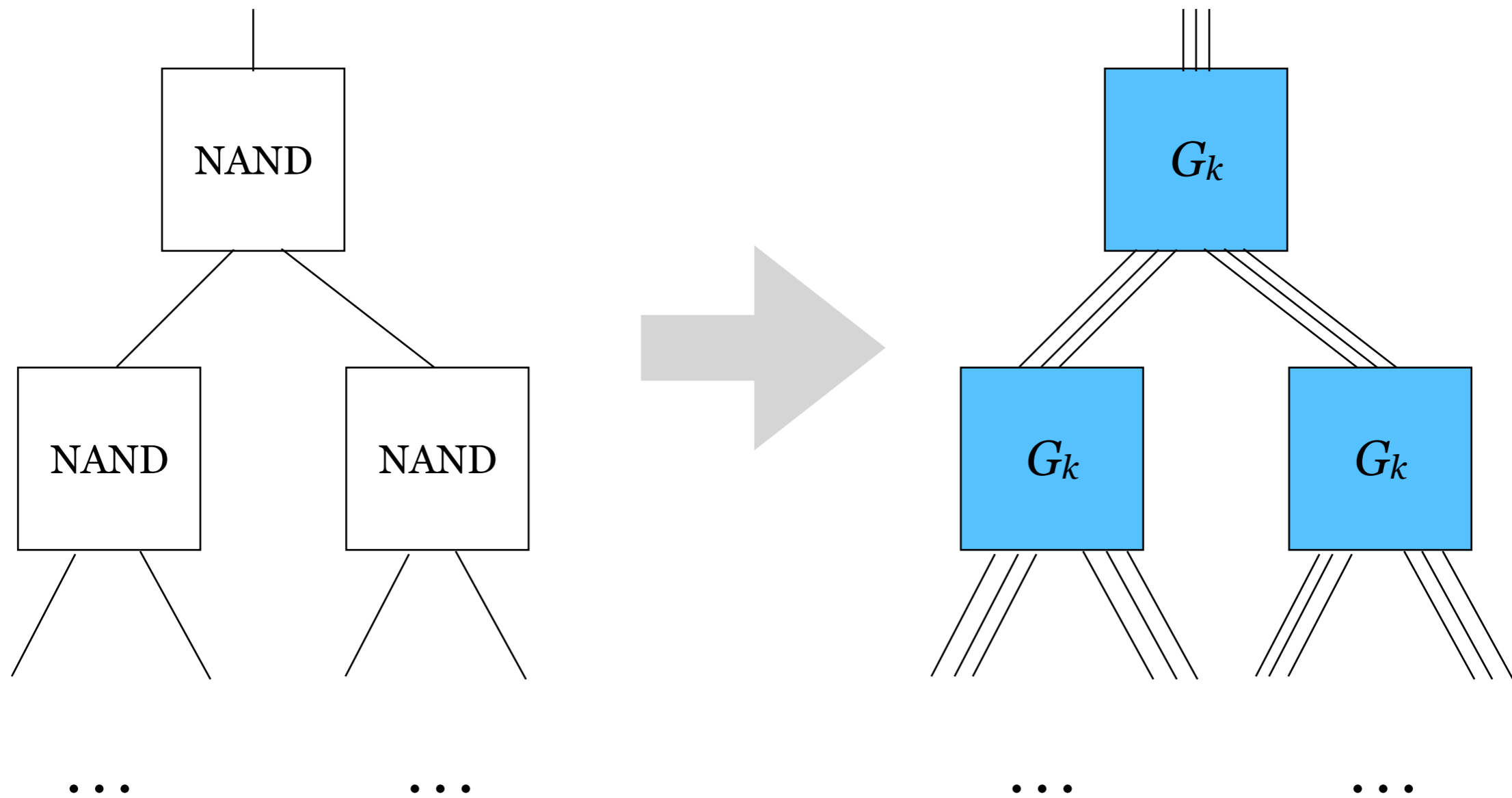


To compile a large circuit  $C$ ,



Stitch together the gadgets for every gate in the circuit

To compile a large circuit C,



**Compositional issues?**

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  - $G_k$  has randomness locality  $O(k)$
  - $k=O(\log(t))$
  - [IKLOPSZ13] “small” randomness locality implies “small” randomness complexity

# Conclusion

- Worst-case wire-probing attacks:
  - *Randomness complexity  $t^{1+\varepsilon}$  (optimal)*
  - *Prior to our work: randomness complexity  $t^{3+\varepsilon}$*
- Random wire-probing attacks:
  - *Simpler construction using elementary tools*

**Thanks!**